

Corrections to “A Low Phase Error Vector Modulator Using TEST Tunable I/Q Generator for mmWave Communication”

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IN the above letter [1], the title was written as: “A Low Phase Error Vector Modulator Using TEST Tunable I/Q Generator for mmWave Communication.” It should have been correctly written as: “A Low Phase Error Vector Modulator Using Tunable I/Q Generator for mmWave Communication.” The authors regret to notify the readers of IEEE MICROWAVE AND WIRELESS TECHNOLOGY LETTERS about this error and apologize.

REFERENCES

- [1] J. Kim, S. Oh, and J. Oh, “A low phase error vector modulator using TEST tunable I/Q generator for mmWave communication,” *IEEE Microw. Wireless Technol. Lett.*, early access, May 8, 2023, doi: [10.1109/LMWT.2023.3270660](https://doi.org/10.1109/LMWT.2023.3270660).

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